

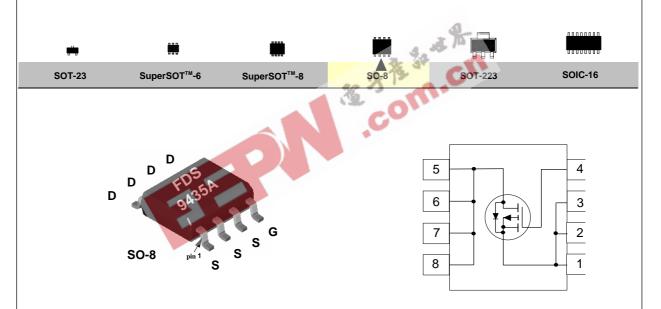
FDS9435A Single P-Channel Enhancement Mode Field Effect Transistor

GeneralDescription

SO-8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.

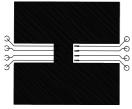


Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

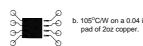
Symbol	Parameter		FDS9435A	Units
V _{DSS}	Drain-Source Voltage		-30	V
V_{GSS}	Gate-Source Voltage		-20	V
I _D	Drain Current - Continuous	(Note 1a)	- 5.3	A
	- Pulsed		-50	
P_{D}	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
Γ_{J} , T_{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS	·		·
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)		50	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-C	ase (Note 1)	25	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \ I_{D} = -250 \mu\text{A}$	-30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 °C		-25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	CTERISTICS (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-1	-1.5	-3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 °C		-3.2		mV/°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -5.3 \text{ A}$		0.035	0.045	Ω
		T _J =125°C		0.052	0.072	1
		$V_{GS} = -4.5 \text{ V}, I_{D} = -4.0 \text{ A}$		0.059	0.075	1
I _{D(ON)}	On-State Drain Current	$V_{GS} = -10 \text{ V}, \ V_{DS} = -5 \text{ V}$	-25			Α
g _{FS}	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_D = -4 \text{ A}$		9.5		S
DYNAMIC C	HARACTERISTICS	4 3 1				
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$		730		pF
C _{oss}	Output Capacitance	t = 1.0 MHz		400		pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		90		pF
SWITCHING	CHARACTERISTICS (Note 2)					,
t _{D(on)}	Turn - On Delay Time	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ A}$		11	20	ns
t _r	Turn - On Rise Time	V_{GS} = -10 V , R_{GEN} = 6 Ω		10	18	
$t_{D(off)}$	Turn - Off Delay Time			90	125	
t,	Turn - Off Fall Time			55	80	
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -4 \text{ A},$		19	27	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V		3.5		
Q_{gd}	Gate-Drain Charge			3.6		
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAXIN	IUM RATINGS				
l _s	Maximum Continuous Drain-Source Diode Forward Current				-2.1	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.1 \text{ A} \text{ (Note 2)}$]	-0.77	-1.2	V

^{1.} $R_{\rm gaA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\rm gaC}$ is guaranteed by design while $\mathbf{R}_{_{\boldsymbol{\theta} CA}}$ is determined by the user's board design.



a. 50°C/W on a 1 in² pad of 2oz copper.





Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

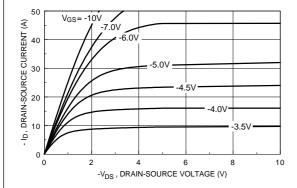


Figure 1. On-Region Characteristics.

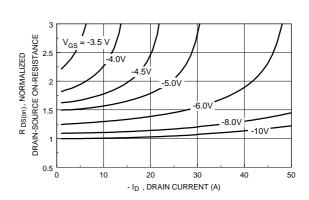


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

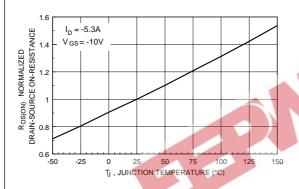


Figure 3. On-Resistance Variation with Temperature.

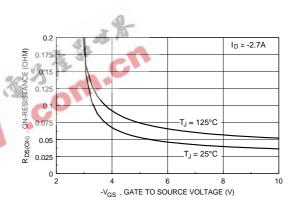


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

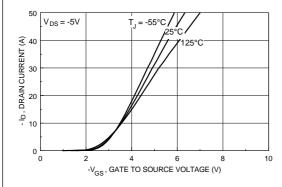


Figure 5. Transfer Characteristics.

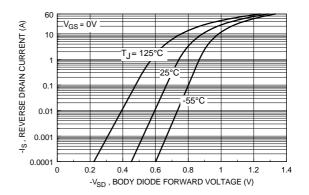
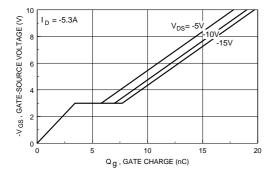


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)



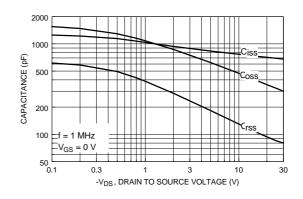
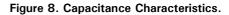
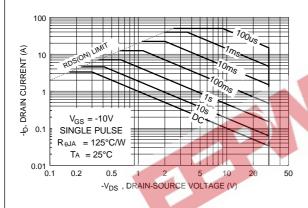


Figure 7. Gate Charge Characteristics.





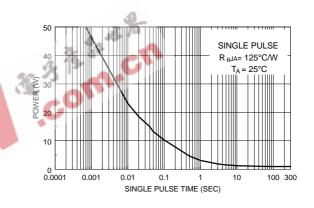


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

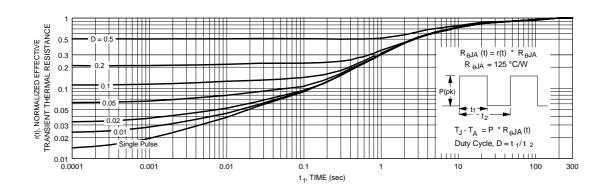
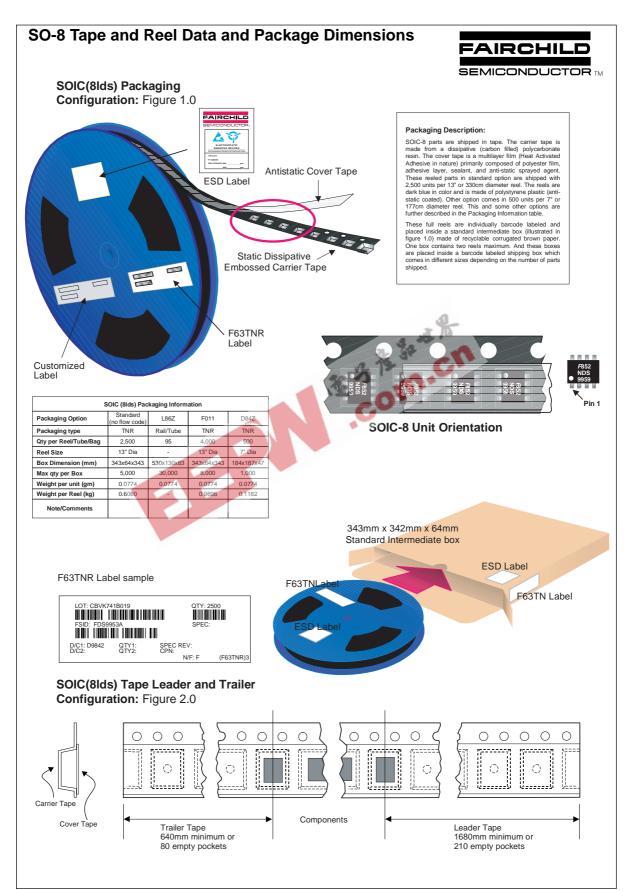
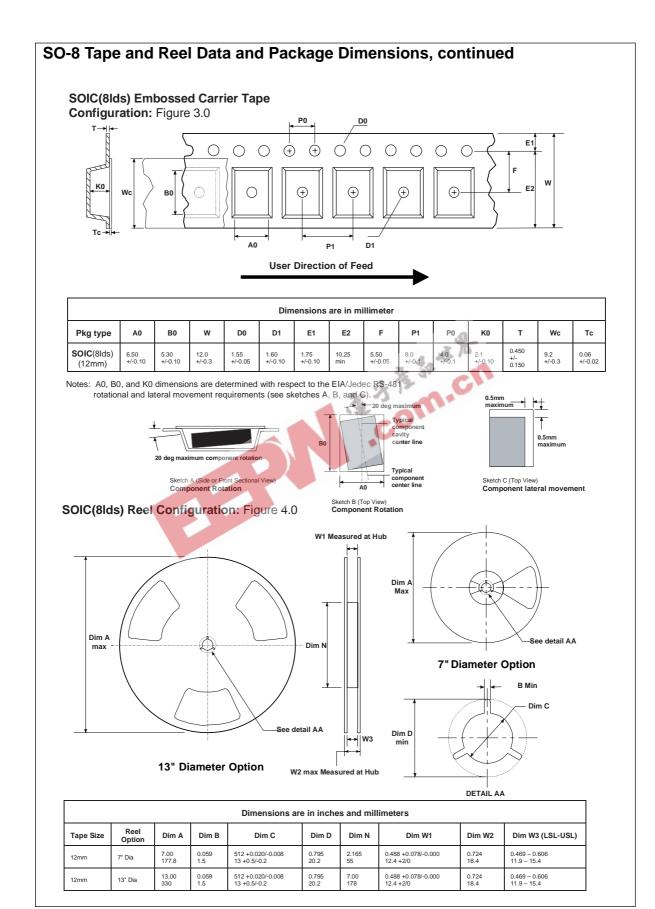
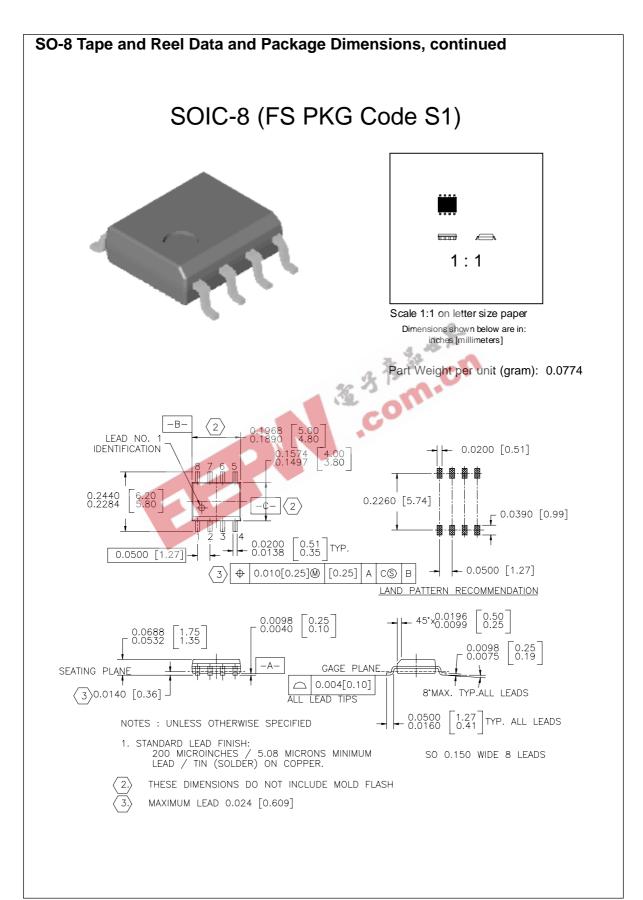


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.







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